

**Search Notes**

Application/Control No.

10/046,859

Examiner

Hien Tran

Applicant(s)/Patent under  
Reexamination

BOEHNKE ET AL.

Art Unit

1764

**SEARCHED**

Class	Subclass	Date	Examiner
422	177, 180, 179, 221, 222	11/18/2005	HT
60	299	11/18/2005	HT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Image class/subclass search / Inventors' names search / text search	11/18/2005	HT